5250 MHz

Measurement Report for Device, , , UID 0 -, Channel 0 (5250.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW,	5250.000,	5.57	4.60	35.2
HSL			0	0			

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt)	HBBL-600-10000 Charge:xxxx, 2024-Apr-	EX3DV4 - SN7383, 2023-06-05	DAE3 Sn427, 2023-05-17
- XXXX	22		

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

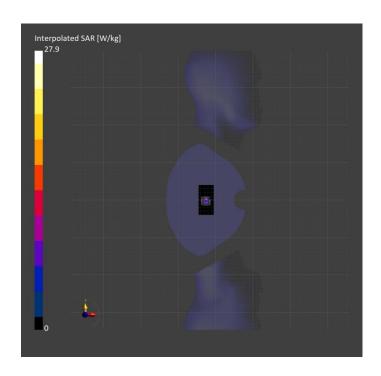
Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-22, 09:02	2024-04-22, 09:09
psSAR1g [W/kg]	6.02	7.20
psSAR10g [W/kg]	1.77	2.08
Power Drift [dB]	0.09	0.17
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		64.6
Dist 3dB Peak [mm]		7.2

Warning(s) / Error(s)

Details Area Scan Zoom Scan

Warning(s) Error(s)



5600 MHz

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Measurement Report for Device, , , UID 0 -, Channel 0 (5600.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW,	5600.000,	5.01	5.19	36.4
HSL			0	0			

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt)	HBBL-600-10000 Charge:xxxx, 2024-Apr-	EX3DV4 - SN7383, 2023-06-05	DAE3 Sn427, 2023-05-17
- YYYY	22		

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

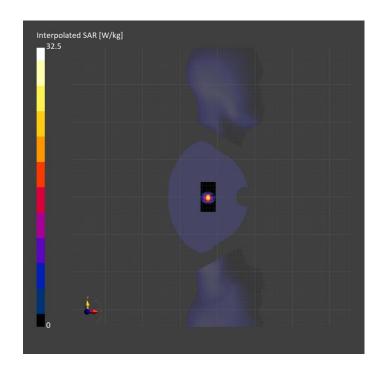
Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-22, 11:57	2024-04-22, 12:05
psSAR1g [W/kg]	7.12	7.91
psSAR10g [W/kg]	2.07	2.27
Power Drift [dB]	0.01	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		62.2
Dist 3dB Peak [mm]		7.6

Warning(s) / Error(s)

B	A C	76
Details	Area Scan	Zoom Scan
Marning(s)		

Warning(s) Error(s)



Measurement Report for Device, , , UID 0 -, Channel 0 (5750.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW,	5750.000,	5.08	5.23	36.0
HSI			0	0			

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt)	HBBL-600-10000 Charge:xxxx, 2024-Apr-	EX3DV4 - SN7383, 2023-06-05	DAE3 Sn427, 2023-05-17
- XXXX	22		

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-22, 12:44	2024-04-22, 12:53
psSAR1g [W/kg]	7.71	7.65
psSAR10g [W/kg]	2.25	2.27
Power Drift [dB]	0.00	-0.15
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		60.1
Dist 3dB Peak [mm]		7.6

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		

Error(s)

